

KATHMANDU UNIVERSITY  
End Semester Examination  
February, 2025

Marks Scored:

Level : B.E.

Year : III

Exam Roll No. :

Registration No.:

Time: 30 mins.

Course : EEEG 320

Semester : II

F. M. : 10

Date

7.1 FEB 2025

SECTION "A"

[20 Q. × 0.5 = 10 marks]

**Choose and encircle the most appropriate option from each set of choices**

- Don't care conditions can be used for simplifying Boolean expressions in \_\_\_\_\_  
a. Registers                      b. Terms                      c. K-maps                      d. Latches
- Half-adders have a major limitation in that they cannot \_\_\_\_\_  
a. Accept a carry bit from a present stage  
b. Accept a carry bit from a next stage  
c. Accept a carry bit from a previous stage  
d. Accept a carry bit from the following stages
- How many outputs will a decimal-to-BCD encoder have?  
a. 4                      b. 8                      c. 12                      d. 16
- In a stable logic state TTL devices consume substantially \_\_\_\_\_ power than equivalent CMOS.  
a. less                      b. more                      c. equal                      d. very high
- Which of the following is not the advantage of MOS gates?  
a. Low power dissipation                      b. Small size  
c. Good immunity to noise                      d. High switching speeds
- Which of the following VHDL design units contain the description of the circuit?  
a. Configurations                      b. Architecture                      c. Library                      d. Entity
- How many times will this process print "EEEG 320"?  
process is  
begin  
    report "EEEG 320";  
    wait for 10 ns;  
end process;  
a. Only one time                      b. Always 11 times  
c. Always 10 times                      d. Depends on for how long we simulate
- In VHDL, which keyword is used to specify ports?  
a. Port\_name                      b. Value\_port                      c. Port                      d. Pt
- Which of the following memories must be refreshed many times per second?  
a. Static RAM                      b. Dynamic RAM                      c. ROM                      d. EPROM

10. ROM is made up of \_\_\_\_\_
- a. NAND and OR gates
  - b. NOR and decoder
  - c. Decoder and OR gates
  - d. NAND and decoder
11. If the output is currently at logic state 1 and after the input changes its state, the output momentarily changes to 0 before settling on 1, then it is a
- a. Static-1 hazard
  - b. Static-0 hazard
  - c. Dynamic hazard
  - d. Functional hazard
12. A Condition occurs when an Asynchronous sequential circuit changes two or more binary states variables is known as
- a. deadlock condition
  - b. Running condition
  - c. Race condition
  - d. Livelock
13. What does ASIC stand for in the context of integrated circuits?
- a. Automated System Integration Circuit
  - b. Advanced System Integrated Circuit
  - c. Analog Signal Integrated Circuit
  - d. Application Specific Integrated Circuit
14. What is the main disadvantage of a Full Custom ASIC design approach?
- a. Easy and quick design process
  - b. Limited customization options
  - c. Low performance output
  - d. High design time, complexity, and cost
15. PLAs, CPLDs, and FPGAs are all which type of device?
- a. SLD
  - b. PLD
  - c. EPROM
  - d. SRAM
16. A ROM of size  $M \times N$  bits can store
- a.  $N$  words of  $M$  bits each
  - b.  $M$  words of  $N$  bits each
  - c.  $M$  bits
  - d.  $N$  bits
17. For the PAL design of a logic circuit, a single literal term
- a. requires an AND gate
  - b. does not require an AND gate
  - c. requires an AND gate and one input for OR gate
  - d. requires an inverter
18. The major difficulty in sequential circuit testing is in
- a. determining output
  - b. determining internal state
  - c. determining external state
  - d. determining input combinations
19. The critical path is the path between
- a. Two combinational circuits
  - b. Two sequential circuits
  - c. Two decoders
  - d. Two multiplexers
20. \_\_\_\_\_ is not a strategy to improve timing of a digital circuit design.
- a. Add register layer
  - b. Parallel structure
  - c. Folding
  - d. Retiming

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F. M. : 40

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SECTION "B"

[4 Q. × 10 = 40 marks]

*Attempt ANY FOUR questions. Each question carries 10 marks. Symbols have their usual meanings. Urgent appropriate assumptions are permissible. Marks are indicated inside brackets.*

1.
  - a. Differentiate Mealy and Moore sequential circuits. [3]
  - b. Compare the characteristics of TTL and CMOS logic families. Explain analytically the behavior of a CMOS based NAND gate with its diagram. [2+2]
  - c. Realize the Boolean function  $F(X,Y,Z)=\sum(1,3,4,5)$  using logic gates for hazard free. [3]
  
2.
  - a. What is the advantage of using PLDs in the design of digital systems? Discuss static hazards in digital circuits with examples. [1+2]
  - b. An asynchronous sequential circuit is described by the following excitation and output and output function,  
 $Y_1 = X_1X_2 + X_1Y_2 + X_2Y_1$   
 $Y_2 = X_2 + X_1Y_1Y_2 + X_1Y_1$   
 $Z = X_2 + Y_1$ 
    - i) Draw the logic diagram of the circuit.
    - ii) Derive the transition table and output map. [4]
  - c. Explain the concept of "entity" and "architecture" in VHDL. State the difference between signal and a variable in VHDL. [2+1]
  
3.
  - a. Design a logic diagram for a gray to binary conversion. Write a VHDL code for the gray to binary conversion. [3+3]
  - b. Differentiate between custom ICs and ASICs. [2]
  - c. Discuss fully associative cache mapping techniques in brief. [2]
  
4.
  - a. Explain system partitioning and routing in FPGA design flow. [3]
  - b. Design following functions using PLA.  
 $Y_1 = AB + AC' + AB'$   
 $Y_2 = AB + A'C + AC$  [4]
  - c. List the advantages and disadvantages of asynchronous sequential circuit. [3]
  
5.
  - a. Explain an architecture of FPGA with a diagram. [3]
  - b. What are the different levels at which testing is carried out? Differentiate between delay fault model and bridging fault model. [2+2]
  - c. Explain how folding and resource sharing helps to optimize area while designing digital circuit. [3]